

<b>FORM PTO-1449 U.S. Department of Commerce</b> <b>Patent and Trademark Office</b>  <b>List of Documents Cited by Applicant</b>	Application No.:	10/615,842
	Filing Date:	July 10, 2003
	First Named Inventor:	Oh
	Group:	1795
	Examiner:	Phasge, Arun S.
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EXAMINER \_\_\_\_\_ DATE CONSIDERED \_\_\_\_\_

\*Examiner Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.